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FDS86141

N-Channel Power Trench[®] MOSFET

100 V, 7 A, 23 mΩ

Features

- Max $r_{DS(on)}$ = 23 mΩ at $V_{GS} = 10$ V, $I_D = 7$ A
- Max $r_{DS(on)}$ = 36 mΩ at $V_{GS} = 6$ V, $I_D = 5.5$ A
- High performance trench technology for extremely low $r_{DS(on)}$
- 100% UIL Tested
- RoHS Compliant

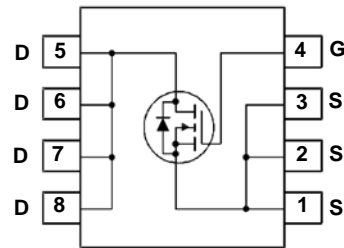
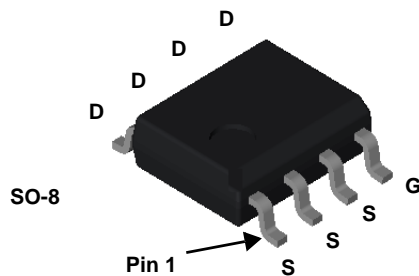


General Description

This N-Channel MOSFET is produced using ON Semiconductor's advanced Power Trench[®] process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

Applications

- DC-DC Conversion



MOSFET Maximum Ratings $T_A = 25$ °C unless otherwise noted

Symbol	Parameter	Rated	Units
V_{DS}	Drain to Source Voltage	100	V
V_{GS}	Gate to Source Voltage	±20	V
I_D	Drain Current -Continuous	7	A
	-Pulsed	30	
E_{AS}	Single Pulse Avalanche Energy (Note 3)	121	mJ
P_D	Power Dissipation $T_A = 25$ °C (Note 1a)	2.5	W
	Power Dissipation $T_A = 25$ °C (Note 1b)	1.0	
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	°C/W
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Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDS86141	FDS86141	SO-8	13 "	12 mm	2500 units

Electrical Characteristics $T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = 250\text{ }\mu\text{A}$, $V_{GS} = 0\text{ V}$	100			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\text{ }\mu\text{A}$, referenced to $25\text{ }^\circ\text{C}$		67		mV/ $^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 80\text{ V}$, $V_{GS} = 0\text{ V}$			1	μA
I_{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20\text{ V}$, $V_{DS} = 0\text{ V}$			± 100	nA

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 250\text{ }\mu\text{A}$	2	3.1	4	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250\text{ }\mu\text{A}$, referenced to $25\text{ }^\circ\text{C}$		-10		mV/ $^\circ\text{C}$
$r_{DS(on)}$	Static Drain to Source On Resistance	$V_{GS} = 10\text{ V}$, $I_D = 7\text{ A}$		19	23	m Ω
		$V_{GS} = 6\text{ V}$, $I_D = 5.5\text{ A}$		27	37	
		$V_{GS} = 10\text{ V}$, $I_D = 7\text{ A}$, $T_J = 125\text{ }^\circ\text{C}$		33	40	
g_{FS}	Forward Transconductance	$V_{DS} = 10\text{ V}$, $I_D = 7\text{ A}$		19		S

Dynamic Characteristics

C_{iss}	Input Capacitance	$V_{DS} = 50\text{ V}$, $V_{GS} = 0\text{ V}$, $f = 1\text{ MHz}$		703	934	pF
C_{oss}	Output Capacitance			186	247	pF
C_{rss}	Reverse Transfer Capacitance			8.6	13	pF
R_g	Gate Resistance			0.5		Ω

Switching Characteristics

$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 50\text{ V}$, $I_D = 7\text{ A}$, $V_{GS} = 10\text{ V}$, $R_{GEN} = 6\text{ }\Omega$		8.3	17	ns
t_r	Rise Time			3.2	10	ns
$t_{d(off)}$	Turn-Off Delay Time			14.3	26	ns
t_f	Fall Time			3.2	10	ns
$Q_{g(TOT)}$	Total Gate Charge		$V_{GS} = 0\text{ V}$ to 10 V		11.8	16.5
	Total Gate Charge	$V_{GS} = 0\text{ V}$ to 5 V	$V_{DD} = 50\text{ V}$, $I_D = 7\text{ A}$	6.7	9.4	nC
Q_{gs}	Total Gate Charge			3.4		nC
Q_{gd}	Gate to Drain "Miller" Charge			3.1		nC

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0\text{ V}$, $I_S = 7\text{ A}$ (Note 2)		0.8	1.3	V
		$V_{GS} = 0\text{ V}$, $I_S = 2\text{ A}$ (Note 2)		0.8	1.2	
t_{rr}	Reverse Recovery Time	$I_F = 7\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$		43	69	ns
Q_{rr}	Reverse Recovery Charge			39	62	nC

NOTES:

1. $R_{\theta JA}$ is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 50 $^\circ\text{C}/\text{W}$ when mounted on a 1 in² pad of 2 oz copper.



b) 125 $^\circ\text{C}/\text{W}$ when mounted on a minimum pad.

2. Pulse Test: Pulse Width < 300 μs , Duty cycle < 2.0 %.

3. Starting $T_J = 25\text{ }^\circ\text{C}$; N-ch: $L = 3\text{ mH}$, $I_{AS} = 9\text{ A}$, $V_{DD} = 100\text{ V}$, $V_{GS} = 10\text{ V}$.

Typical Characteristics $T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted

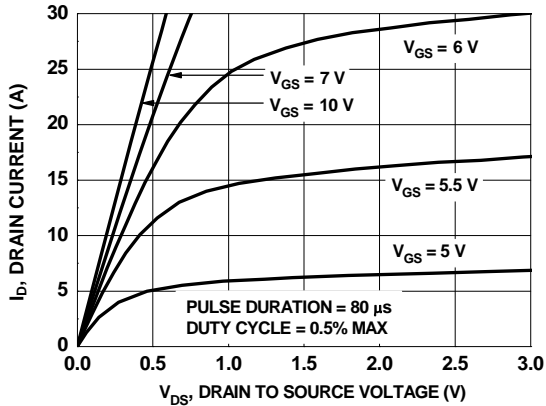


Figure 1. On-Region Characteristics

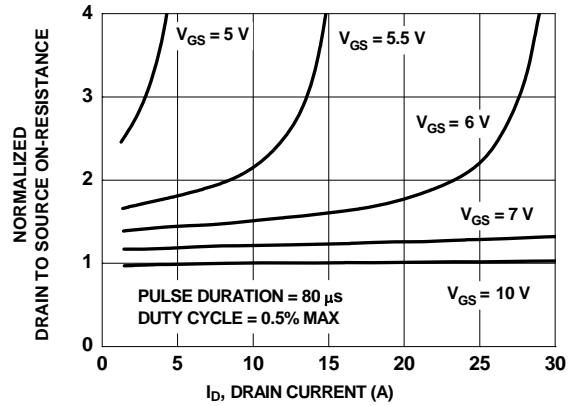


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

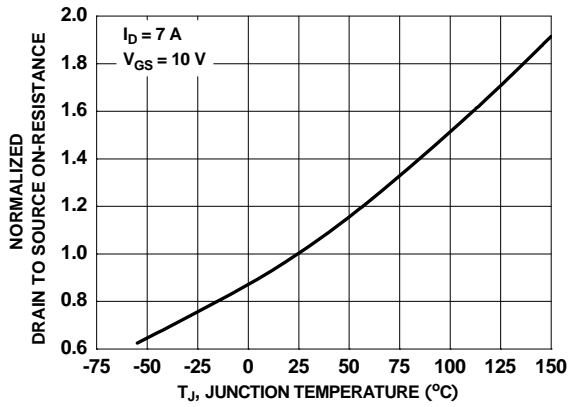


Figure 3. Normalized On-Resistance vs Junction Temperature

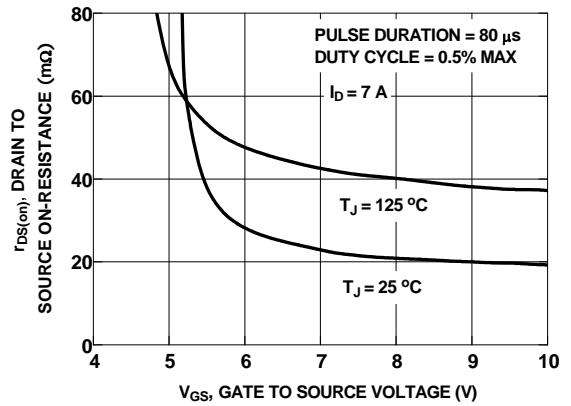


Figure 4. On-Resistance vs Gate to Source Voltage

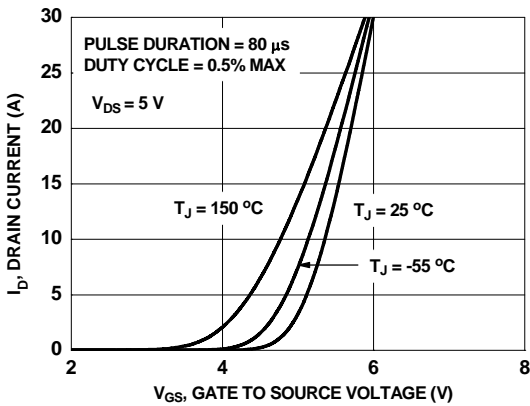


Figure 5. Transfer Characteristics

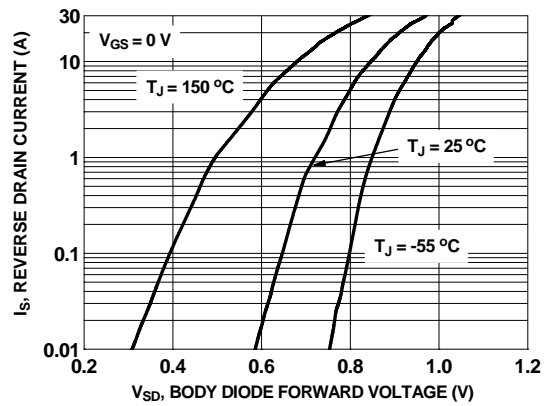


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted

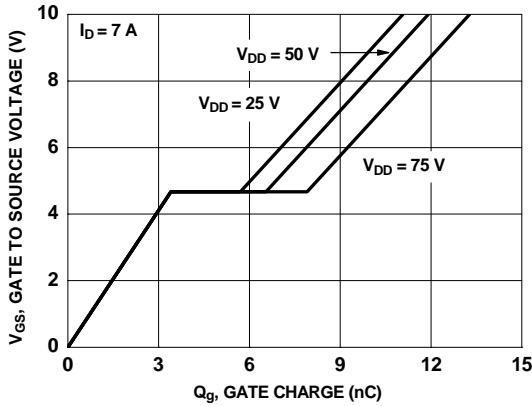


Figure 7. Gate Charge Characteristics

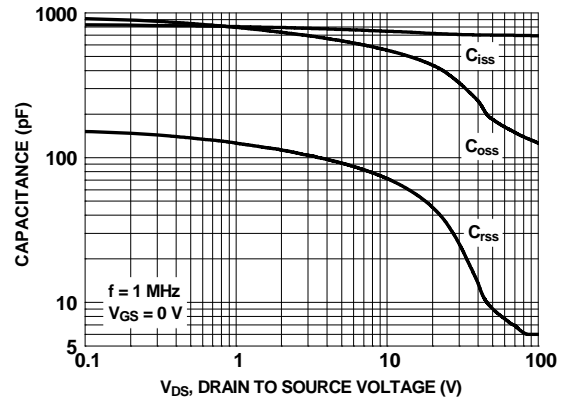


Figure 8. Capacitance vs Drain to Source Voltage

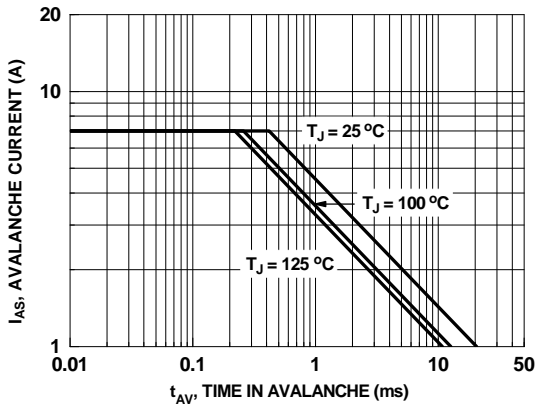


Figure 9. Unclamped Inductive Switching Capability

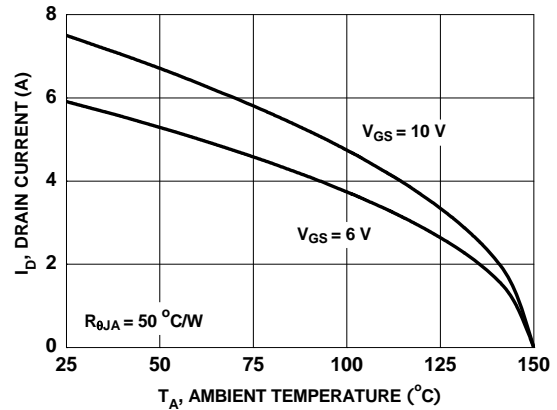


Figure 10. Maximum Continuous Drain Current vs Ambient Temperature

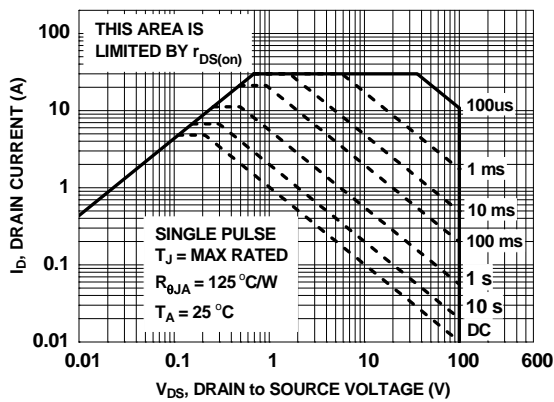


Figure 11. Forward Bias Safe Operating Area

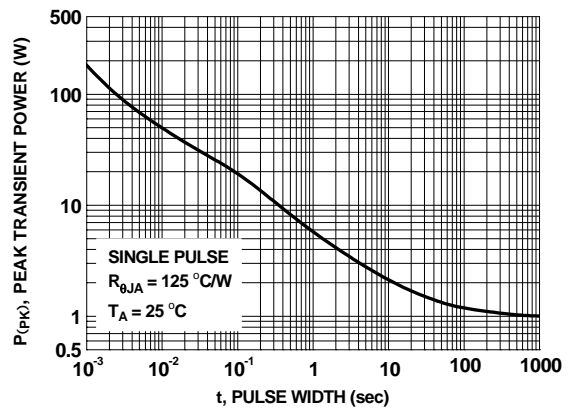


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics $T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted

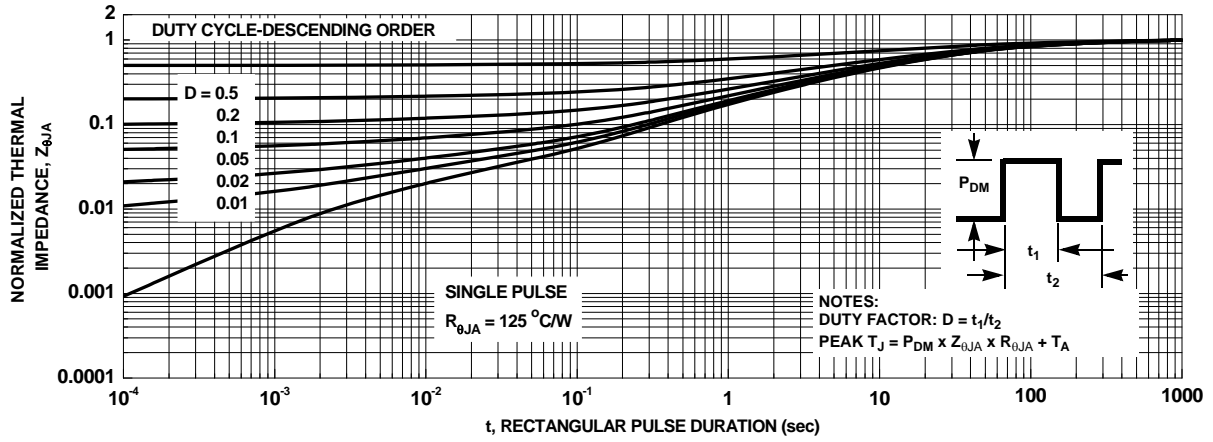
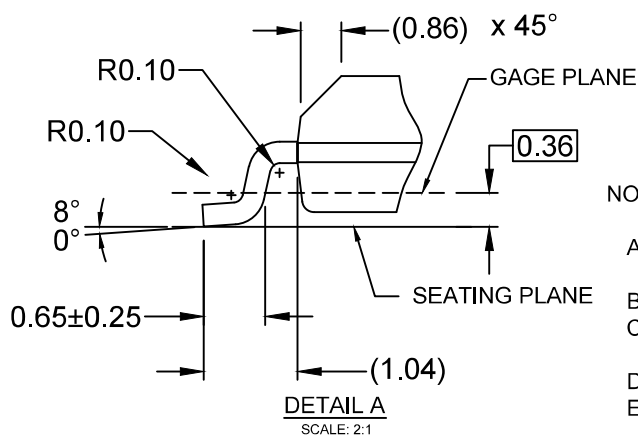
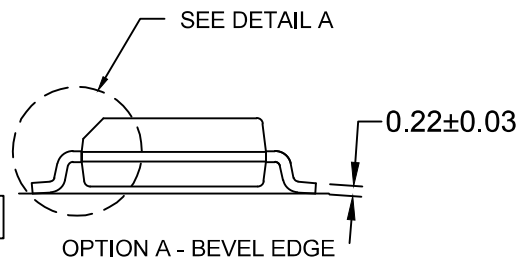
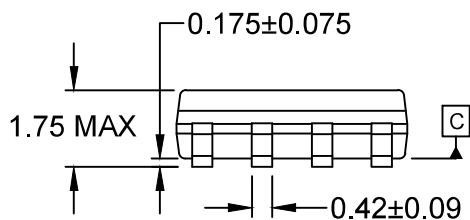
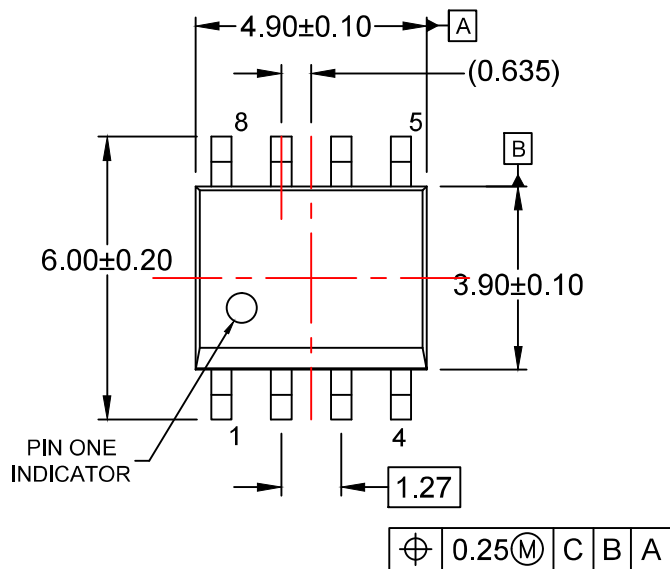


Figure 13. Junction-to-Ambient Transient Thermal Response Curve



NOTES:

- A) THIS PACKAGE CONFORMS TO JEDEC MS-012, VARIATION AA.
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS DO NOT INCLUDE MOLD FLASH OR BURRS.
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- E) DRAWING FILENAME: M08Arev16



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